Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/687,085	MAEDA, HIROSHI
Examiner	Art Unit
Stephen W. Smoot	2813

Class	Subclass	Date	Examiner	:
438	108	1/12/2005	sws	
438	118	1/12/2005	sws	
438	126	1/12/2005	sws	
438	127	1/12/2005	sws	J.W.g
438	132	1/12/2005	sws	
438	601	1/12/2005	sws	
438	612	1/12/2005	sws	
438	613	1/12/2005	sws	
438	958	1/12/2005	sws	Z
Updated	Above	5/23/2005	sws	P.D.L.

INTERFERENCE SEARCHED

Subclass

Date

5/23/2005

Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
Key Words: Chip, Die, IC - Pad; Solder - Bump, Ball; Polyimide; Passivation; Fuse;	1/12/2005	J.W.L. sws			
Chip Carrier, Package Substrate, Wiring Substrate; Flip Chip Assembly; Underfilled.	1/12/2005	8.W.S.			
Updated Above Search	5/23/2005	L.J.S.			
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	1/12/2005 & 5-73-05	sws L.W.S			

Same as Above

Class